

HIGH TEMP AEC-Q200 INDUCTORS - EPI07018Q1 SERIES



FEATURE

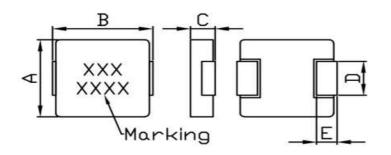
- 1. Shielded construction, Frequency range up to 5MHz
- 2. AEC-Q200 Grade 1 qualified

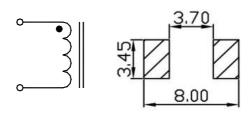
Applications

1. Notebook, server application, High current power supplier

● Shape and Dimension

• Schematics and Land Patterns(mm)





A=6.80m/m Max; B=7.30m/m Max; C=1.80m/m Max; D=3.00±0.3m/m; E=1.50m/m Ref.;

Specification

P/N	L	RDC	Isat	Irms
	(µH)	(mΩ)Max	(A)	(A)
EPI07018Q1-R33M	0.33±20%	7.0	18.0	12.0
EPI07018Q1-R68M	0.68±20%	13.9	15.0	9.0
EPI07018Q1-R82M	0.82±20%	15.9	14.0	8.0
EPI07018Q1-1R0M	1.0±20%	18.5	11.5	7.0
EPI07018Q1-1R5M	1.5±20%	34.0	10.0	6.0
EPI07018Q1-2R2M	2.2±20%	46.0	8.5	5.0
EPI07018Q1-3R3M	3.3±20%	60.1	6.0	3.25
EPI07018Q1-4R7M	4.7±20%	78.0	5.5	3.0
EPI07018Q1-6R8M	6.8±20%	136	4.5	2.5
EPI07018Q1-100M	10±20%	195	4.0	2.0
EPI07018Q1-220M	22±20%	600	2.5	1.0

Note1. Measurement frequency of Inductance value: at 100KHz

Note2. Measurement ambient temperature of L, DCR and IDC : at 25° C

Note3. Isat: DC current at which the inductance drops 20%(typ) from its value without current

Note4. Irms: Average current for 40°C temperature rise from 25°C ambient(typical)

Note5. Inductance tolerance: M: ±20% Note6. Packaging: Taping: 1500 Piece/reel



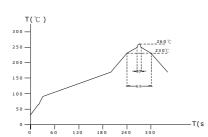
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GENERAL CHARACTERISTICS

- 1. Operating temperature range: -55 TO + 125°C (Includes temperature when the coil is heated)
- 2. High temperature exposure(storage) refer MIL-STD-202 Method 108: 1000 hrs at rated operating temperature(e.g. 125°C). Part can be stored for 1000 hrs @125°C. Unpowered. Measurement at 24±4 hours after test conclusion.
- 3. Temperature cycling refer JESD22 Method JA-104: 1000 cycles(-55 TO + 125℃). Measurement at 24±4 hours after test conclusion. 30 min maximum dwell time at each temp. extreme. 1 min. maximum transition time.
- 4. Biased Humidity refer MIL-STD-202 Method 103: 1000 hours 85℃/85%RH. Unpowered. Measurement at 24±4 hours after test conclusion.
- Operational Life refer MIL-PRF-27: 1000 hrs. at 125 [°]C tested. Measurement at 24±4 hours after test conclusion.
- 6. External Visual refer MIL-STD-883 Method 2009: Inspect device construction, marking and workmanship.
- 7. Physical Dimension refer JESD22 Method JB-100: Verify physical dimensions to the applicable device detail specification.
- Resistance to Solvents refer MIL-STD-202 Method 215: Add aqueous wash chemical OKEM clean or equivalent.
- 9. Mechanical Shock refer MIL-STD-202 Method 213: Figure 1 of Method 213. Condition C.
- 10. Vibration refer MIL-STD-202 Method 204: 5g;s for 20 minutes, 12 cycles each of 3 orientations. Test from 10-2000 Hz.
- 11. Resistance to soldering Heat refer MIL-STD-202 Method 210: Condition B No pre-heat of samples. Single wave solder-procedure 2 for SMD and procedure 1 for leaded with solder within 1.5mm of device body.
- 12. ESD refer AEC-Q200-002 or ISO/DIS 10605: Direct contact discharge 2kV.
- 13. Solderability refer J-STD-002: For both Leaded & SMD. Magnification 50X. Conditions: Leaded, Method A@235℃, category 3; SMD, a)Method B, 4hrs@125℃ dry heat @235℃, b)Method B@215℃ category 3., c)Method D category 3@260℃
- 14. Electrical Characterization refer spec: Show Min, Max Mean and Standard deviation at room from Min and Max temperature.
- 15. Flammability refer UL-94: V-0 or V-1 Acceptable.
- 16. Board Flex refer AEC-Q200-005: 60 sec minimum holding time.
- 17. Terminal Strength(SMD) refer AEC-Q200-006
- 18. Reflow profile recommend:

Lead-free heat endurance test



Lead-free the recommended reflow condition

